

## Quarterly Reliability Monitoring Results

Quarters: 04/2018 to 03/2019

Based on structural similarity

Supplier		User Part Number				
Nexperia B.V.		PESD5V0V2BMB				
Name of Laboratory		Part Description				
Assembly reliability labs		Nexperia DHAM		Protection		
MCD package						
AEC-Q101 Test	Test Conditions	Duration	# Lots	# Quantity	# Rejects	
# 1	<b>TEST</b> Pre- and Post-Stress Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below
# 2	<b>PC</b> Preconditioning	JESD22-A113 Bake Tamb = 125 °C Soak Tamb = 85 °C, RH = 85% Reflow soldering	24 hours 168 hours 3 cycles	109	8690	0
# 5	<b>HTRB</b> High Temperature Reverse Bias	MIL-STD-750-1 M1038 Method A Tj = Tjmax, Vr = 100% of max. datasheet reverse voltage	1000 hours	99	7920	0
# 7	<b>TC</b> Temperature Cycling	JESD22-A104 -55 °C to Tjmax, not to exceed 150°C	1000 cycles	42	3345	0
# 8	<b>AC</b> Autoclave	JESD22-A102 Tamb = 121 °C, RH = 100 % Pressure = 205 kPa (29.7 psia)	96 hours	26	2080	0
# 9	<b>H3TRB</b> High Humidity High Temperature Reverse Bias	JESD22-A101 Tamb = 85 °C, RH = 85%, VR > 80 % of rated reverse voltage	1000 hours	41	3265	0
# 10	<b>IOL</b> Intermittent Operating Life	MIL-STD-750 Method 1037 ton = toff, devices powered to insure ΔTj = 100 °C for 15000 cycles	1000 hours	n.a.	n.a.	n.a.
# 20	<b>RSH</b> Resistance to Solder Heat	JESD22-A111 260 °C ± 5 °C	10 s	n.a.	n.a.	n.a.
# 21	<b>SD</b> Solderability	J-STD-002 Test method B and D		27	270	0

### Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, AEC-Q101 Test # 5)

Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM	Protection	7920	0	0,54	1,87E+09

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